# N-Channel Enhancement Mode Power MOSFET

# Description

The HM80N03 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

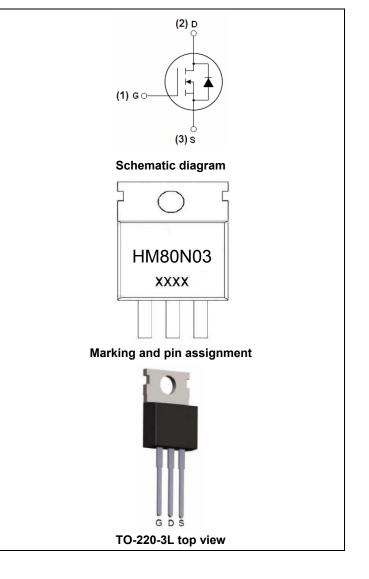
## **General Features**

- V<sub>DS</sub> =30V,I<sub>D</sub> =80A
  R<sub>DS(ON)</sub> <6.5mΩ @ V<sub>GS</sub>=10V
  R<sub>DS(ON)</sub> < 10mΩ @ V<sub>GS</sub>=5V
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation

# Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

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## Package Marking and Ordering Information

| Device Marking | Device  | Device Package | Reel Size | Tape width | Quantity |
|----------------|---------|----------------|-----------|------------|----------|
| HM80N03        | HM80N03 | TO-220-3L      | -         | -          | -        |

## Absolute Maximum Ratings (T<sub>c</sub>=25<sup>°</sup>Cunless otherwise noted)

| Parameter  | Symbol                | Limit      | Unit |
|--|-----------------------|------------|------|
| Drain-Source Voltage                             | Vds                   | 30         | V    |
| Gate-Source Voltage                              | Vgs                   | ±20        | V    |
| Drain Current-Continuous                         | I <sub>D</sub>        | 80         | А    |
| Drain Current-Continuous(T <sub>C</sub> =100℃)   | I <sub>D</sub> (100℃) | 50         | A    |
| Pulsed Drain Current                             | I <sub>DM</sub>       | 170        | A    |
| Maximum Power Dissipation                        | PD                    | 83         | W    |
| Derating factor                                  |                       | 0.56       | W/°C |
| Single pulse avalanche energy (Note 5)           | E <sub>AS</sub>       | 306        | mJ   |
| Operating Junction and Storage Temperature Range | TJ,TSTG               | -55 To 175 | °C   |

## **Thermal Characteristic**

| Thermal Resistance, Junction-to-Case(Note 2) | R <sub>θJC</sub> | 1.8 | °C/W |
|--|------------------|-----|------|
|--|------------------|-----|------|

## Electrical Characteristics (T<sub>c</sub>=25°C unless otherwise noted)

| Parameter                          | Symbol              | Condition   | Min | Тур  | Max  | Unit |  |
|------------------------------------|---------------------|---|-----|------|------|------|--|
| Off Characteristics                |                     |   | •   |      |      |      |  |
| Drain-Source Breakdown Voltage     | BV <sub>DSS</sub>   | V <sub>GS</sub> =0V I <sub>D</sub> =250µA                           | 30  | -    | -    | V    |  |
| Zero Gate Voltage Drain Current    | I <sub>DSS</sub>    | V <sub>DS</sub> =30V,V <sub>GS</sub> =0V                            | -   | -    | 1    | μA   |  |
| Gate-Body Leakage Current          | I <sub>GSS</sub>    | $V_{GS}$ =±20V, $V_{DS}$ =0V  | -   | -    | ±100 | nA   |  |
| On Characteristics (Note 3)        |                     |   |     |      |      |      |  |
| Gate Threshold Voltage             | V <sub>GS(th)</sub> | V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =250µA             | 1   | 1.6  | 3    | V    |  |
| Drain-Source On-State Resistance   | 5                   | V <sub>GS</sub> =10V, I <sub>D</sub> =30A                           | -   | 5.5  | 6.5  |      |  |
| Dialit-Source Off-State Resistance | R <sub>DS(ON)</sub> | V <sub>GS</sub> =5V, I <sub>D</sub> =24A                            | -   | 7.5  | 10   | mΩ   |  |
| Forward Transconductance           | <b>g</b> fs         | V <sub>DS</sub> =5V,I <sub>D</sub> =24A                             | 20  | -    | -    | S    |  |
| Dynamic Characteristics (Note4)    | ·                   |   | •   |      |      |      |  |
| Input Capacitance                  | C <sub>lss</sub>    |   | -   | 2330 | -    | PF   |  |
| Output Capacitance                 | C <sub>oss</sub>    | V <sub>DS</sub> =15V,V <sub>GS</sub> =0V,<br>F=1.0MHz               | -   | 460  | -    | PF   |  |
| Reverse Transfer Capacitance       | C <sub>rss</sub>    |   | -   | 230  | -    | PF   |  |
| Switching Characteristics (Note 4) |                     |   |     |      |      |      |  |
| Turn-on Delay Time                 | t <sub>d(on)</sub>  |   | -   | 20   | -    | nS   |  |
| Turn-on Rise Time                  | tr                  | V <sub>DD</sub> =10V,I <sub>D</sub> =30A                            | -   | 15   | -    | nS   |  |
| Turn-Off Delay Time                | t <sub>d(off)</sub> | $V_{GS}$ =10V, $R_{GEN}$ =2.7 $\Omega$                              | -   | 60   | -    | nS   |  |
| Turn-Off Fall Time                 | t <sub>f</sub>      |   | -   | 10   | -    | nS   |  |
| Total Gate Charge                  | Qg                  | V <sub>DS</sub> =10V,I <sub>D</sub> =30A,                           | -   | 51   | -    | nC   |  |
| Gate-Source Charge                 | Q <sub>gs</sub>     | $V_{\rm DS}$ -10V,1D-30A,<br>V <sub>GS</sub> =10V                   | -   | 14   | -    | nC   |  |
| Gate-Drain Charge                  | Q <sub>gd</sub>     | V <sub>GS</sub> -10V  | -   | 11   | -    | nC   |  |
| Drain-Source Diode Characteristics |                     |   |     |      |      |      |  |
| Diode Forward Voltage (Note 3)     | V <sub>SD</sub>     | V <sub>GS</sub> =0V,I <sub>S</sub> =24A                             | -   | -    | 1.2  | V    |  |
| Diode Forward Current (Note 2)     | I <sub>S</sub>      |   | -   | -    | 80   | А    |  |
| Reverse Recovery Time              | t <sub>rr</sub>     | TJ = 25°C, IF = 80A   | -   | 32   | 50   | nS   |  |
| Reverse Recovery Charge            | Qrr                 | di/dt = 100A/µs(Note3)  | -   | 12   | 20   | nC   |  |
| Forward Turn-On Time               | t <sub>on</sub>     | Intrinsic turn-on time is negligible (turn-on is dominated by LS+LI |     |      |      |      |  |

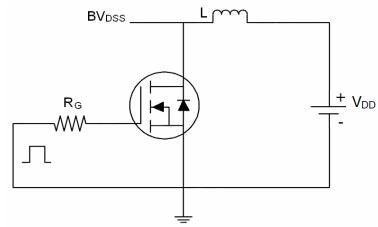
#### Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board,  $t \le 10$  sec.
- **3.** Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2%.
- 4. Guaranteed by design, not subject to production
- **5.** EAS condition: Tj=25  $^\circ C$  ,V\_DD=15V,V\_G=10V,L=0.5mH,Rg=25\Omega, I\_{AS}=35A

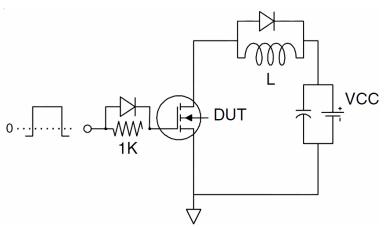
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# Test Circuit

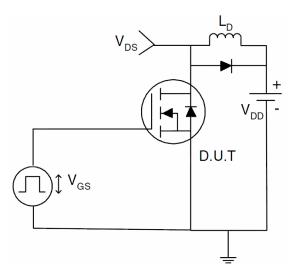
1) E<sub>AS</sub> Test Circuits



# 2) Gate Charge Test Circuit:

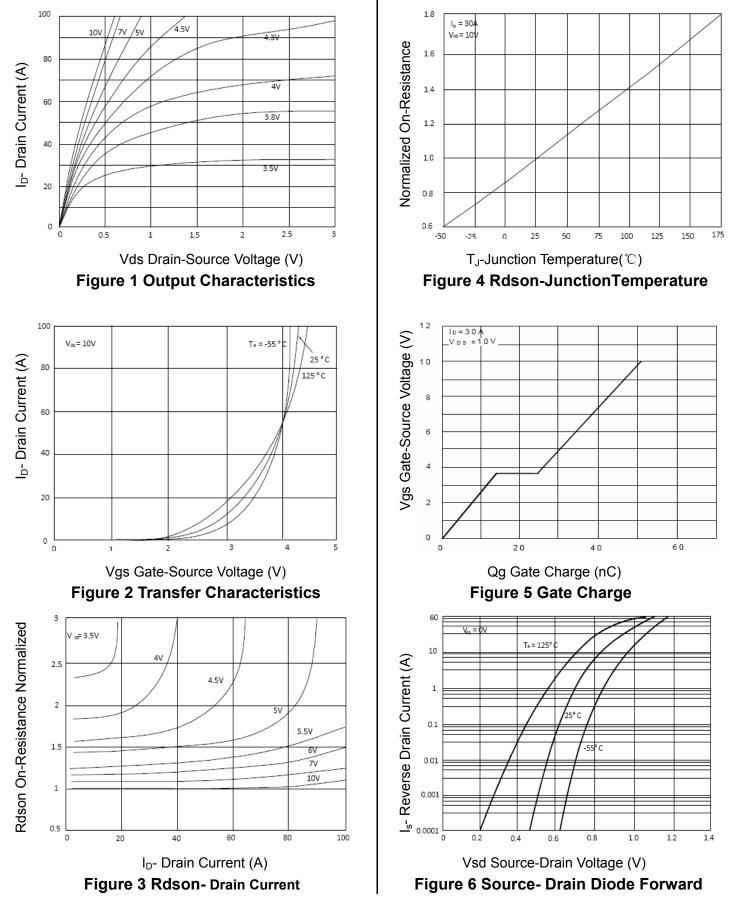


3) Switch Time Test Circuit:



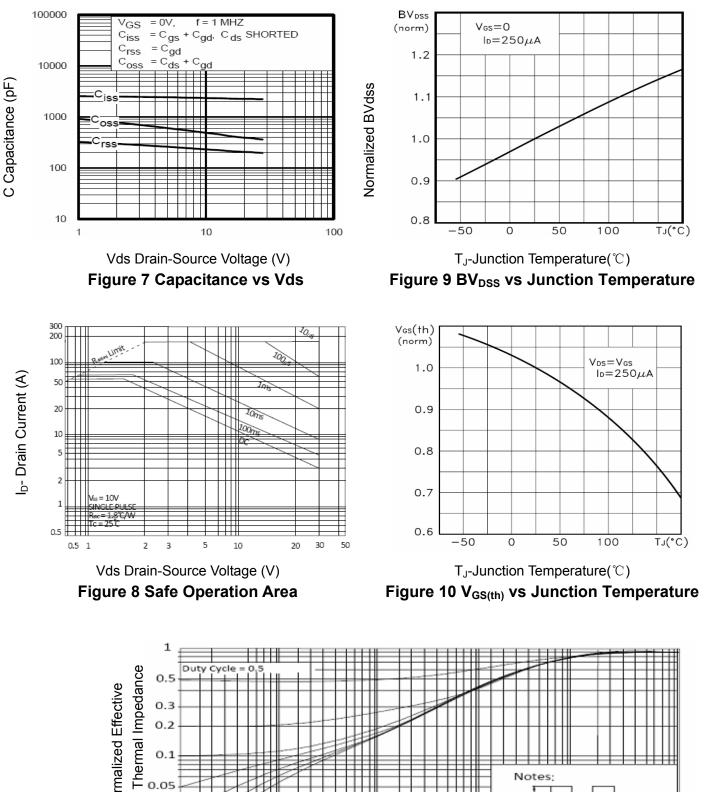
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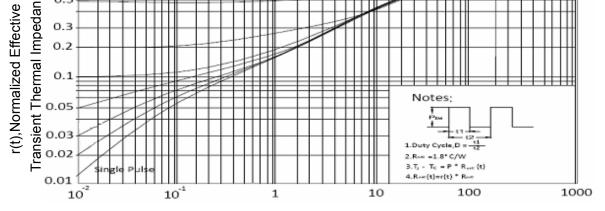
# **Typical Electrical and Thermal Characteristics (Curves)**



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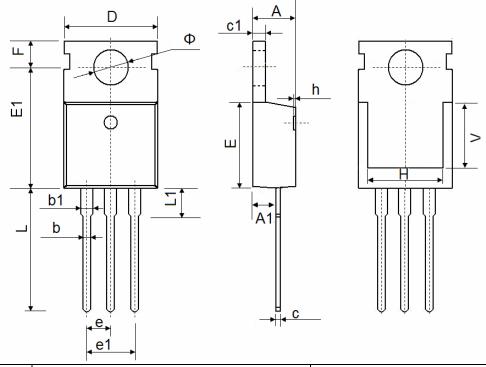
# HM80N03





Square Wave Pluse Duration(sec) Figure 11 Normalized Maximum Transient Thermal Impedance

# TO-220-3L Package Information



| Symbol | Dimensions | In Millimeters | Dimensions In Inches |            |  |  |
|--------|------------|----------------|----------------------|------------|--|--|
|        | Min.       | Max.           | Min.                 | Max.       |  |  |
| A      | 4.400      | 4.600          | 0.173                | 0.181      |  |  |
| A1     | 2.250      | 2.550          | 0.089                | 0.100      |  |  |
| b      | 0.710      | 0.910          | 0.028                | 0.036      |  |  |
| b1     | 1.170      | 1.370          | 0.046                | 0.054      |  |  |
| с      | 0.330      | 0.650          | 0.013                | 0.026      |  |  |
| c1     | 1.200      | 1.400          | 0.047                | 0.055      |  |  |
| D      | 9.910      | 10.250         | 0.390                | 0.404      |  |  |
| E      | 8.9500     | 9.750          | 0.352                | 0.384      |  |  |
| E1     | 12.650     | 12.950         | 0.498                | 0.510      |  |  |
| е      | 2.540      | 2.540 TYP.     |                      | 0.100 TYP. |  |  |
| e1     | 4.980      | 5.180          | 0.196                | 0.204      |  |  |
| F      | 2.650      | 2.950          | 0.104                | 0.116      |  |  |
| Н      | 7.900      | 8.100          | 0.311                | 0.319      |  |  |
| h      | 0.000      | 0.300          | 0.000                | 0.012      |  |  |
| L      | 12.900     | 13.400         | 0.508                | 0.528      |  |  |
| L1     | 2.850      | 3.250          | 0.112                | 0.128      |  |  |
| V      | 7.500 REF. |                | 0.295 REF.           |            |  |  |
| Φ      | 3.400      | 3.800          | 0.134                | 0.150      |  |  |

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